# Test Spring School 2019

## Rastatt, Germany
## May 24-27 2019

Held in conjunction with the
24th IEEE European Test Symposium
www.ieee-ets.org

**T·S·S@ETS** 19
Test Spring School

## Cutting Edge Approaches for Test

**Co-organized with H2020 RESCUE and DFG SPP 1500**

The European Test Symposium (ETS'19) offers the 3 days Test Spring School (TSS@ETS 2019, May 24-27) for Ph.D. and M.Sc. students who will be introduced into most up-to-date concepts in test, reliability, security, etc. Renowned experts will give lectures and will cover the main challenges of hardware test issues and infrastructures. The spring school also offers the state of the art of test, design for test, and test generation and validation of digital and analog circuits.

The overall theme of this year is *Cutting Edge Approaches for Test.* The first two lectures cover issues related to novelties in defect modeling and test strategies, design for test and test applications. The third and fourth lectures cover formal techniques in test generation and beyond, and infrastructure for test and diagnosis. One of the last two lectures covers system level testing whereas the other lecture covers analog, mixed-signal and RF IC testing with integrated test approaches.

The spring school is organized in conjunction with ETS 2019, and the last two lectures are open for the general ETS audience without additional fee. This year TSS 2019 is financially supported by several companies, namely **Advantest, Intel and Mentor Graphics (a Siemens business).** The spring school is also organized in cooperation with H2020 RESCUE European Training Network, and German Research Foundation's Priority Program on "Dependable Embedded Systems" (DFG SPP 1500).

TSS@ETS is offered to registered students at low cost rate. There will also be a bundle student rate registration for both TSS and ETS, at exceptionally low rate. The spring school is also open for professionals at higher rates, however priority is given to students on first-come, first-served basis, as the number of attendees is strictly limited.

### Friday, May 24th
18:00 **Welcome and introduction**

### Saturday, May 25th
08:00 **Faults, Defects and Test Strategies**
*P. Maxwell, ON Semiconductor*

13:30 **Infrastructure for Test, Debug, and Diagnosis** *(part I)*
*J. Rearick, AMD*

### Sunday, May 26th
08:00 **Infrastructure for Test, Debug, and Diagnosis** *(part II)*
*J. Rearick, AMD*

09:15 **Design for Test and Test Applications** *(part I)*
*J. Rajski, Mentor, A Siemens Business*

13:30 **Design for Test and Test Applications** *(part II)*
*J. Rajski, Mentor, A Siemens Business*

14:45 **Formal Techniques in Test Generation** *(part I)*
*R. Drechsler, University of Bremen / DFKI Bremen*

### Monday, May 27th
08:30 **Formal Techniques in Test Generation** *(part II)*
*R. Drechsler, University of Bremen / DFKI Bremen*

14:00 **Track A: Analog, Mixed-Signal, RF IC Testing: Essentials and Current Trends**
*H.G. Stratigopoulos, Sorbonne Université, CNRS, LIP6*

**Track B: System-Level Testing**
*H. Chen, MediaTek*

**Test Spring School Venue**
Bildungshaus St. Bernhard
Ludwigsfeste 50, 76437
Rastatt, Germany
www.st-bernhard-rastatt.de

**Organizing Committee**
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